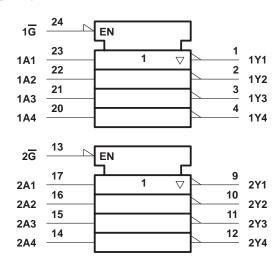
- Flow-Through Architecture Optimizes PCB Layout
- Center-Pin V<sub>CC</sub> and GND Configurations Minimize High-Speed Switching Noise
- EPIC<sup>™</sup> (Enhanced-Performance Implanted CMOS) 1-μm Process
- 500-mA Typical Latch-Up Immunity at 125°C
- Package Options Include Plastic Small-Outline Packages, Plastic Shrink Small-Outline Packages, Ceramic Chip Carriers, and Standard Plastic and Ceramic 300-mil DIPs

#### description

These octal buffers/line drivers are designed specifically to improve both the performance and density of 3-state memory address drivers, clock drivers, and bus-oriented receivers and transmitters. These devices provide inverting outputs and symmetrical  $\overline{\mathbf{G}}$  (active-low output control) inputs. These devices feature high fan-out and improved fan-in.

The 54AC11240 is characterized for operation over the full military temperature range of  $-55^{\circ}$ C to 125°C. The 74AC11240 is characterized for operation from  $-40^{\circ}$ C to  $85^{\circ}$ C.

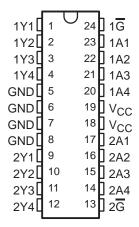
### logic symbol†



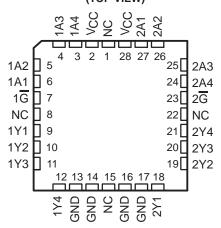
<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the DW, JT, and NT packages.

#### 54AC11240 . . . JT PACKAGE 74AC11240 . . . DB, DW OR NT PACKAGE (TOP VIEW)



## 54AC11240 . . . FK PACKAGE (TOP VIEW)



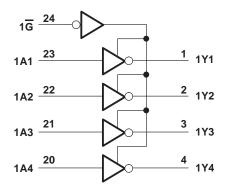
NC - No internal connection

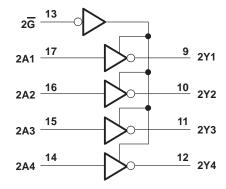
### FUNCTION TABLE (each buffer)

INP	UTS	OUTPUT
G	Α	Y
L	Н	L
L	L	Н
Н	Χ	Z

EPIC is a trademark of Texas Instruments Incorporated.

#### logic diagram (positive logic)





Pin numbers shown are for the DW, JT, and NT packages.

### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V <sub>CC</sub>	0.5 V to 6 V
Input voltage range, V <sub>I</sub> (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Output voltage range, V <sub>O</sub> (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, $I_{IK}$ ( $V_I < 0$ or $V_I > V_{CC}$ )	±20 mA
Output clamp current, I <sub>OK</sub> (V <sub>O</sub> < 0 or V <sub>O</sub> > V <sub>CC</sub> )	±50 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$	±50 mA
Continuous current through V <sub>CC</sub> or GND	±200 mA
Storage temperature range	65°C to 150°C

<sup>†</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTE 1: The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

#### recommended operating conditions

			54	4AC1124	0	74AC11240		LINUT	
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vсс	Supply voltage		3	5	5.5	3	5	5.5	V
		VCC = 3 V	2.1			2.1			
ViH	High-level input voltage	V <sub>CC</sub> = 4.5 V	3.15			3.15			V
		$V_{CC} = 5.5 \text{ V}$	3.85			3.85			
		VCC = 3 V			0.9			0.9	
$\vee_{IL}$	Low-level input voltage	V <sub>CC</sub> = 4.5 V			1.35			1.35	_
		V <sub>CC</sub> = 5.5 V			1.65			1.65	
٧ı	Input voltage		0		Vcc	0		Vcc	V
۷o	Output voltage		0		Vсс	0		Vcc	V
	High-level output current	V <sub>CC</sub> = 3 V			-4			-4	
IOH		V <sub>CC</sub> = 4.5 V			-24			-24	mA
		V <sub>CC</sub> = 5.5 V			-24			-24	
		V <sub>CC</sub> = 3 V			12			12	
lOL	Low-level output current	V <sub>CC</sub> = 4.5 V			24			24	mA
		V <sub>CC</sub> = 5.5 V			24			24	
Δt/Δν	Input transition rise or fall rate	G	0		5	0		5	ns/V
\(\alpha\tau\)		Data	0		10	0		10	
TA	Operating free-air temperature		-55		125	-40		85	°C



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# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	V	Т,	<sub>A</sub> = 25°C	54AC11	240	74AC11240		UNIT
PARAMETER		Vcc	MIN	TYP MAX	MIN	MAX	MIN	MAX	
	Ι <sub>ΟΗ</sub> = – 50 μΑ	3 V	2.9		2.9		2.9		
		4.5 V	4.4		4.4		4.4		
		5.5 V	5.4		5.4		5.4		
Vali	I <sub>OH</sub> = - 4 mA	3 V	2.58		2.4		2.48		V
VOH	I <sub>OH</sub> = -24 mA	4.5 V	3.94		3.7		3.8		V
	10H = - 24 IIIA	5.5 V	4.94		4.7		4.8		
	$I_{OH} = -50 \text{ mA}^{\dagger}$	5.5 V			3.85				
	$I_{OH} = -75 \text{ mA}^{\dagger}$	5.5 V					3.85		
	I <sub>OL</sub> = 50 μA	3 V		0.1		0.1		0.1	
		4.5 V		0.1		0.1		0.1	
		5.5 V		0.1		0.1		0.1	
Va.	I <sub>OL</sub> = 12 mA	3 V		0.36		0.5		0.44	V
VOL	I <sub>OL</sub> = 24 mA	4.5 V		0.36		0.5		0.44	V
		5.5 V		0.36		0.5		0.44	
	$I_{OL} = 50 \text{ mA}^{\dagger}$	5.5 V				1.65			
	$I_{OL} = 75 \text{ mA}^{\dagger}$	5.5 V						1.65	
loz	V <sub>O</sub> = V <sub>CC</sub> or GND	5.5 V		± 0.5		± 10		± 5	μΑ
lį	V <sub>I</sub> = V <sub>CC</sub> or GND	5.5 V		± 0.1		± 1		± 1	μΑ
Icc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V		8		160		80	μΑ
C <sub>i</sub>	$V_I = V_{CC}$ or GND	5 V		4					pF
CO	V <sub>O</sub> = V <sub>CC</sub> or GND	5 V		10					pF

<sup>†</sup> Not more than one output should be tested at a time, and the duration of the test should not exceed 10 ms.

# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 3.3 V $\pm$ 0.3 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	ТО	T,	<sub>Δ</sub> = 25°C	;	54AC1	11240	74AC1	1240	UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
tPLH	А	Y	1.5	7.6	10.5	1.5	12.8	1.5	11.7	no
t <sub>PHL</sub>			1.5	6.3	8.6	1.5	10.2	1.5	9.5	ns
<sup>t</sup> PZH	G	Y	1.5	8.2	11.6	1.5	13.4	1.5	12.7	no
tPZL			1.5	7.6	10.8	1.5	13	1.5	12	ns
<sup>t</sup> PHZ	G	V	1.5	5.5	7.5	1.5	8.1	1.5	7.8	ne
t <sub>PLZ</sub>	G	'	1.5	6.7	9.4	1.5	10	1.5	9.8	ns

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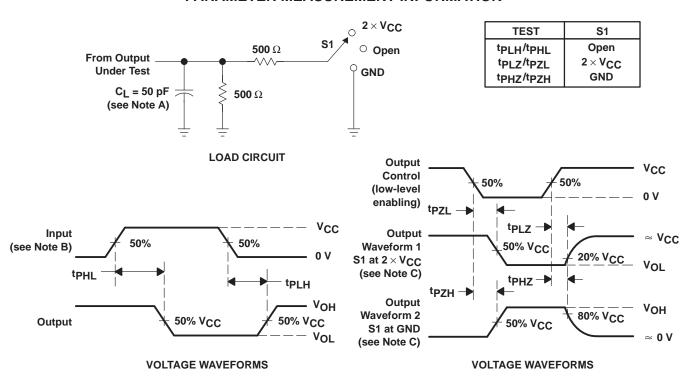
## switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 5 V $\pm$ 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	ТО	T <sub>A</sub> = 25°C			54AC11240		74AC11240		UNIT
PARAMETER	(INPUT)	(OUTPUT)	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT
t <sub>PLH</sub>	А	Y	1.5	5.4	7.5	1.5	9	1.5	8.4	
t <sub>PHL</sub>			1.5	4.6	6.6	1.5	7.8	1.5	7.2	ns
<sup>t</sup> PZH	_	V	1.5	5.7	8.2	1.5	9.9	1.5	9.2	no
tPZL	G	ī	1.5	5.3	7.7	1.5	9.4	1.5	8.7	ns
t <sub>PHZ</sub>	-	V	1.5	4.7	6.3	1.5	6.9	1.5	6.6	no
tPLZ	G	r	1.5	5.2	7.3	1.5	8	1.5	7.7	ns

### operating characteristics, V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25°C

PARAMETER		TEST CONI	TYP	UNIT		
<u> </u>	C <sub>pd</sub> Power dissipation capacitance per buffer	Outputs enabled	C: 50 °F	50 nE f = 1 MHz		pF
Cbq		Outputs disabled	$C_L = 50 \text{ pF},$	f = 1 MHz	12	pr

#### PARAMETER MEASUREMENT INFORMATION



NOTES: A. C<sub>L</sub> includes probe and jig capacitance.

- B. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  10 MHz,  $Z_O = 50 \ \Omega$ ,  $t_f = 3 \ ns$ ,  $t_f = 3 \ ns$ .
- C. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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